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editor-in-chief
Wendy Van Moer
University of Gävle
Department of Electronics, Mathematics
and Natural Sciences
SE-801 76 Gävle, Sweden
wendy.w.vanmoer@ieee.org

associate editor-in-chief
Simona Salicone
simona.salicone@polimi.it

senior editor
June Sudduth
j.sudduth@ieee.org

administrative assistant
Kristy Virostek
virostek5@verizon.net

I&M editorial board
Ruth A. Dyer
Alessandro Ferrero
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Salvatore Baglio
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Ruqiang Yan
Veronica Scotti
Bryan Kibble
Charles Nader
Lee Barford
Kevin Bennet

managing editor
Beverly Lindeen
blindeen@allenpress.com

advertising sales manager
Onkar Sandal
+1 800 627 0932 x218
Fax: +1 785 843 1853
osandal@allenpress.com

on the cover:
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Robert M. Goldberg
1360 Clifton Ave.
PMB 336
Cifton, NJ 07012, USA
E-mail: r.goldberg@ieee.org

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